## Notice of References Cited Application/Control No. 10/003,085 Applicant(s)/Patent Under Reexamination HAYASHI, KEIICHI Examiner X L Bautista Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,137,468	10-2000	Martinez et al.	345/649
	В	US-6,567,983 B1	05-2003	Shiimori, Yoshiko	725/105
	С	US-			**
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-	0	·	
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Р					
	σ					
	R					
	Ø					,
	Т		•			

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	U								
	V								
	w								
	x								

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.